

November 2013

# **FDMS015N04B**

# N-Channel PowerTrench<sup>®</sup> MOSFET 40 V, 100 A, 1.5 m $\Omega$

#### **Features**

- $R_{DS(on)}$  = 1.13 m $\Omega$  (Typ.) @  $V_{GS}$  = 10 V,  $I_D$  = 50 A
- Advanced Package and Silicon Combination for Low R<sub>DS(on)</sub> and High Efficiency
- · Fast Switching Speed
- · 100% UIL Tested
- · RoHS Compliant

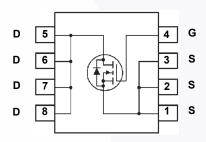
# Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advance PowerTrench® process that has been tailored to minimize the on-state resistance while maintaining superior switching performance.

# **Applications**

- · Synchronous Rectification for ATX / Server
- · Battery Protection Circuit
- · Motor Drives and Uninterruptible Power Supplies





# MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted.

Symbol	Parameter			FDMS015N04B	Unit
V <sub>DSS</sub>	Drain to Source Voltage		40	V	
V <sub>GSS</sub>	Gate to Source Voltage			±20	V
	Drain Current	- Continuous (T <sub>C</sub> = 25°C)		100	۸
I <sub>D</sub> Drain Current	Drain Current	- Continuous (T <sub>A</sub> = 25°C)	(Note 1a)	31.3	Α
I <sub>DM</sub>	Drain Current - Pulsed (Note 2)		400	Α	
E <sub>AS</sub>	Single Pulsed Avalanche Energ	ЭУ	(Note 3)	526	mJ
D	Power Dissipation	(T <sub>C</sub> = 25°C)		104	W
P <sub>D</sub> Power Dissipation		(T <sub>A</sub> = 25°C)	(Note 1a)	2.5	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temper	ature Range		-55 to +150	°C

### **Thermal Characteristics**

Symbol	Parameter	FDMS015N04B	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	1.2	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max. (Note 1	a) 50	- C/VV

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS015N04B	FDMS015N04B	Power 56	13 "	12 mm	3000 units

# **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	cteristics					
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250 \mu\text{A},  V_{GS} = 0 \text{V}$	40	-	-	V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 μA, Referenced to 25°C	-	37	-	mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 32 V, V <sub>GS</sub> = 0 V	-	-	1	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	±100	nA

#### **On Characteristics**

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu\text{A}$	2.0	-	4.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 50 \text{ A}$	-	1.13	1.5	mΩ
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 50 A	-	171	-	S

## **Dynamic Characteristics**

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C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V f = 1 MHz		-	6560	8725	pF
C <sub>oss</sub>	Output Capacitance			-	2795	3720	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			-	162		pF
C <sub>oss</sub> (er)	Energy Releted Output Capacitance	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V		-	3896	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V			-\	91	118	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 50 A		- \	26	-	nC
Q <sub>gs2</sub>	Gate Charge Threshold to Plateau	V <sub>GS</sub> = 0 V to 10 V		-	9	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	(No	te 4)	-	16	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz		-	1.4	-	Ω

# **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		-	34	78	ns
t <sub>r</sub>		$V_{DD} = 20 \text{ V}, I_{D} = 50 \text{ A}$	-	24	58	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_G = 4.7 \Omega$	-	71	152	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)	-/	26	62	ns

#### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diod	Maximum Continuous Drain to Source Diode Forward Current			100	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	400	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	Drain to Source Diode Forward Voltage V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 50 A		-	1.3	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 50 A	-	78	<b>/</b>	ns
Q <sub>rr</sub>	Reverse Recovery Charge			90	-	nC

#### Notes

TAR<sub>9,A</sub> is determined with the device mounted on a 1in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>9,JC</sub> is guaranteed by design while R<sub>9CA</sub> is determined by the user's board design.



a. 50 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



b. 125 °C/W when mounted on a minimum pad of 2 oz copper.

 $<sup>{\</sup>bf 2.} \ {\bf Repetitive} \ {\bf rating:} \ {\bf pulse-width} \ {\bf limited} \ {\bf by} \ {\bf maximum} \ {\bf junction} \ {\bf temperature}.$ 

<sup>3.</sup> L = 3 mH,  $I_{AS}$  = 18.72 A, starting  $T_{J}$  = 25°C.

<sup>4.</sup> Essentially independent of operating temperature typical characteristics.

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

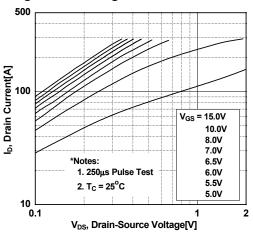


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

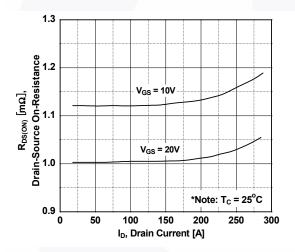


Figure 5. Capacitance Characteristics

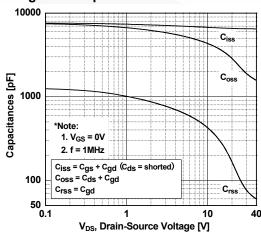


Figure 2. Transfer Characteristics

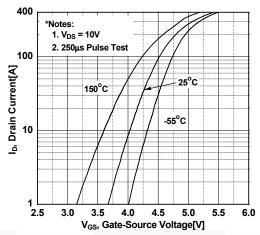


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

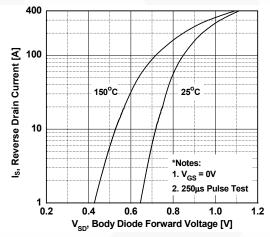
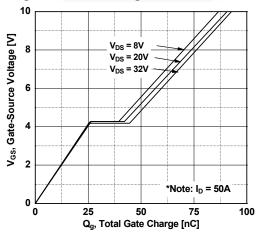


Figure 6. Gate Charge Characteristics



# **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

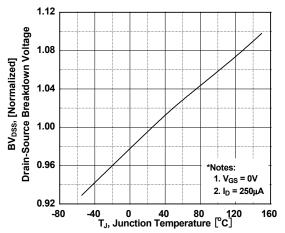


Figure 9. Maximum Safe Operating Area

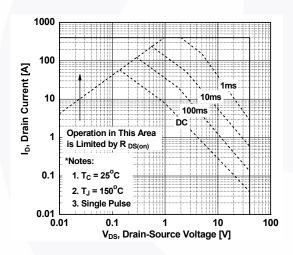


Figure 11. Eoss vs. Drain to Source Voltage

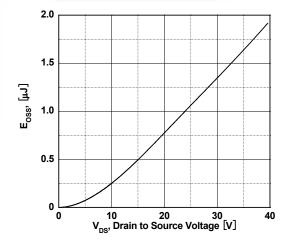


Figure 8. On-Resistance Variation vs. Temperature

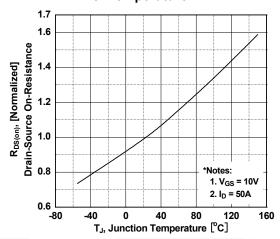


Figure 10. Maximum Drain Current vs. Case Temperature

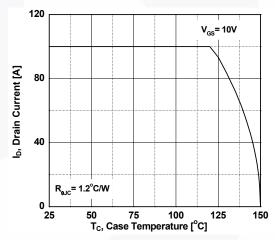
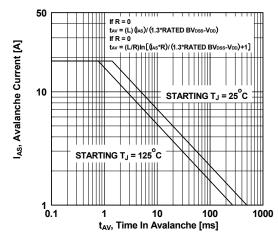


Figure 12. Unclamped Inductive Switching Capability



# **Typical Performance Characteristics** (Continued)

Figure 13. Transient Thermal Response Curve

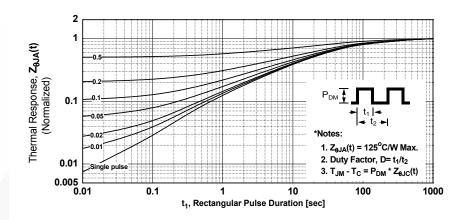


Figure 14. Gate Charge Test Circuit & Waveform

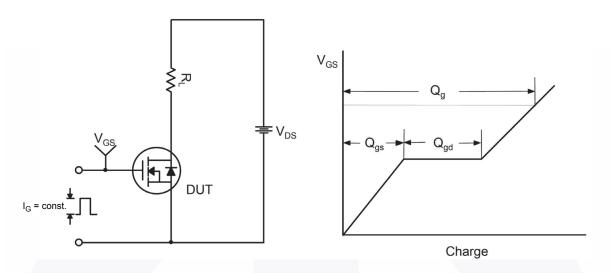


Figure 15. Resistive Switching Test Circuit & Waveforms

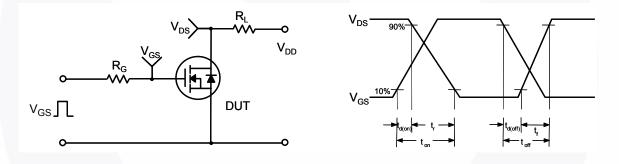
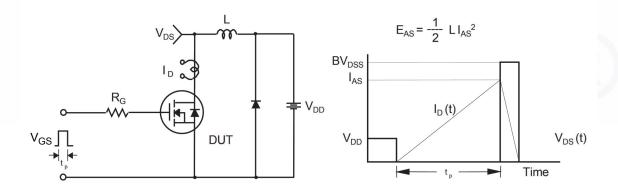


Figure 16. Unclamped Inductive Switching Test Circuit & Waveforms



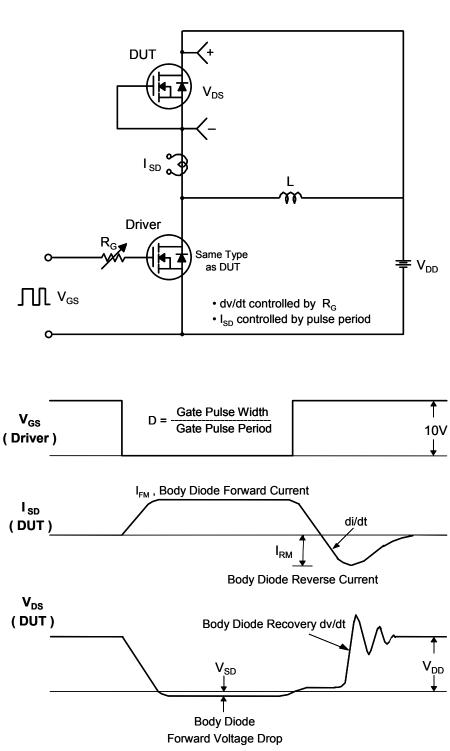


Figure 17. Peak Diode Recovery dv/dt Test Circuit & Waveforms







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Definition of Terms		
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Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
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